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**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Date: December 28, 2009

Page **1** of **1**

Applicant: OKUBO et al.

Appln. No.: 10/544,178

Filing Date: April 24, 2006

Examiner: MOORE, W. Group Art Unit: 2826

U.S. PATENT DOCUMENTS

| Examiner's Initials* | Document Number | Date MM/YYYY | Name (Family Name of First Inventor) | Class | Sub Class | Filing Date (if appropriate) |
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| /W.M./ YR | "Kunio Takayanagi et al., "Semiconductor Measurement Evaluation Dictionary", Japan Science Forum Corporation, September 12, 1997, pages 87-90 | X |
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Examiner **Whitney Moore/** Date Considered: **12/29/2009**

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.